

Bruker Dektak XT Surface Profiler



Surface profiler measures small surface variations in vertical stylus displacement as a function of position. This profiler can measure small vertical features ranging in height from 10 nm to 1 mm.

Specifications

- Stylus profilometry (contact measurement)
- Two-dimensional surface profile measurements
- Stylus Force 1 to 15mg with LIS 3 sensor
- High Aspect Ratio (HAR) tips 10_μm x 2_μm and 200_μm x 20_μm
- Sample X/Y Stage Manual 100mm (4 in.) X/Y, manual leveling
- Sample R-Theta Stage Manual, continuous 360 degrees
- Software Vision64 Operation and Analysis Software
- Scan Length Range 55mm (2in.); 200mm (8in.) with scan stitching capability
- Data Points Per Scan 120,000 maximum
- Max. Sample Thickness 50mm (1.95in.)
- Max. Wafer Size 200mm (8in.)
- Step Height Repeatability <math><5\text{\AA}</math>, 1sigma on 0.1μm step
- Vertical Range 1mm (0.039in.)
- Vertical Resolution 1Å max. (@ 6.55_μm range)